


<b>Search Notes</b>  	<b>Application/Control No.</b>  10538498	<b>Applicant(s)/Patent Under Reexamination</b>  ZHANG ET AL.
	<b>Examiner</b>  STUART W SNYDER	<b>Art Unit</b>  1648

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Dialog: Magnetic or paramagnetic, microbead, cell, separate	5/29/2008	sws
EAST: Magnetic or paramagnetic, microbead, cell, separate; inventors	6/2/2008	sws

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner